



Sheet: 1 of: 1

FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 2003-0076.00/US	Serial No: 10/619,052
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Micron Technology, Inc.	
		Filing Date: July 10, 2003	Group: 1765

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	
LV	AA	5,627,093	05/06/97	Hachisuka et al.	438	649	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
	AO						Yes	No
	AP						<input type="checkbox"/>	<input type="checkbox"/>
	AQ						<input type="checkbox"/>	<input type="checkbox"/>
	AR						<input type="checkbox"/>	<input type="checkbox"/>
	AS						<input type="checkbox"/>	<input type="checkbox"/>
	AT						<input type="checkbox"/>	<input type="checkbox"/>

Initial	OTHER REFERENCES (including author, title, date, pertinent pages, etc.)		
	AU		
	AV		
	AW		
	AX		

Examiner: LAN VINH	Date Considered: 7/1/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.

FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 2003-0076.00/US	Serial No: Not Assigned
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Micron Technology, Inc.	
		Filing Date: July 10, 2003	Group: Not Assigned

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
LV	AA 5,198,384	03/1993	Dennison	437	47	
	AB 5,381,302	01/1995	Sandhu et al.	361	305	
	AC 5,422,296	06/1995	Lage	437	52	
	AD 5,536,683	07/1996	Lin et al.	437	200	
	AE 5,854,127	12/1998	Pan	438	629	
	AF 5,899,742	05/1999	Sun	438	682	
	AG 5,998,257	12/1999	Lane et al.	438	253	
	AH 6,013,547	01/2000	Liaw	438	238	
	AI 6,074,960	06/2000	Lee et al.	438	749	
	AJ 6,096,638	08/2000	Matsubara	438	649	
	AK 6,175,146	01/2001	Lane et al.	257	635	
	AL 6,194,315	02/2001	Hu et al.	438	683	
	AM 6,261,899	07/2001	Lane et al.	438	253	
LV	AN 6,486,060	11/2002	Hermes et al.	438	649	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
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	AP					<input type="checkbox"/>	<input type="checkbox"/>
	AQ					<input type="checkbox"/>	<input type="checkbox"/>
	AR					<input type="checkbox"/>	<input type="checkbox"/>
	AS					<input type="checkbox"/>	<input type="checkbox"/>
	AT					<input type="checkbox"/>	<input type="checkbox"/>

Initial

OTHER REFERENCES (including author, title, date, pertinent pages, etc.)

	AU		
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